

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/863,861	VINJE, VETLE	
	Examiner Toan M Le	Art Unit 2862	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Multiple Weights in Diffraction Stack Migration", Tygel et al., Geophysics, Vol. 59, No. 12, pages 1820-1830, 12/1993
	V	"Angle-Dependent Reflectivity by Means of Prestack Migration", de Bruin et al., Geophysics, Vol. 5, No. 9, pages 1223-1234, 9/1990
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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